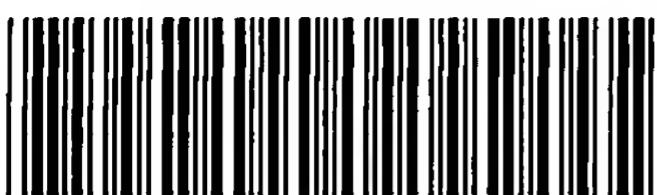


Search Notes



Application/Control No.

10/652,202

Examiner

Benjamin C. Lee

**Applicant(s)/Patent under
Reexamination**

YANAGIDA ET AL.

Art Unit

2612

SEARCHED

INTERFERENCE SEARCHED

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
340	310.11	6/7/07	BN
1	538		
	825,22		
	3.1		
	5.72		
307	10.1		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)